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Special Issue on the 2017 International Image Sensor Workshop (IISW)

Guest Editors:

Mr. Vladimir Koifman

Prof. Dr. Shoji Kawahito

Dr. Daniel Van Blerkom

Dr. Guy Meynants

Deadline for manuscript submissions:

closed (31 October 2017)

Message from the Guest Editors

Dear Colleagues,

The International Image Sensor Workshop (IISW) is the world's largest technology forum, fully devoted to image sensor design and research. The workshop papers span across a wide range of imaging devices: From small pixel mobile image sensors to large format X-ray and astronomy imagers, from sensors for high end scientific applications to low-cost mass produced stacked sensors, from time-resolving and photon counting imagers to rad-hard sensors for space applications.

This Special Issue provides the expanded versions of 20 invited papers from the workshop covering novel and innovative approaches in image sensors, as well as state-of-the-art incremental improvements on known techniques.

Other paper submissions are strictly limited to IISW 2017 participants.

Mr. Vladimir Koifman Prof. Dr. Shoji Kawahito Dr. Guy Meynants

Dr. Daniel Van Blerkom

Guest Editors













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Message from the Editor-in-Chief

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(Instrumentation)

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